

REMARKS

As a preliminary matter, Applicants traverse the Examiner's statement (page 6 of the outstanding Office Action, last two lines) that Applicants arguments from Response F, filed April 5, 2006 were "not formally entered." The Examiner has no legal basis for denying entry of Applicant's remarks from Response F. No amendments were made in Response F, and therefore Response F was an appropriate formal request for reconsideration. The Examiner may not deny entry of a request for reconsideration, even if he does not agree with the arguments. The Examiner may refuse to enter substantive amendments after final rejection, but not arguments against the rejection itself. Applicants therefore respectfully submit that the Examiner must acknowledge in writing that Response F has been formally entered into the record, either in a separate paper, or a corrected version of the outstanding Office Action.

Applicants further submit that the Examiner's statement regarding Response F contradicts the Advisory Action mailed on April 19, 2006. Nowhere in this Advisory Action does the Examiner once indicate that Response F was not formally entered. In fact, item no. 11 on the Advisory Action specifically says that "the request for reconsideration has been considered." Consideration could not have been given by the Examiner unless he first formally entered Response F. Once again, ccorrection is respectfully requested.

Claims 21 and 24 stand rejected under 35 U.S.C. 112, second paragraph, as being indefinite. Specifically, the Examiner, for the first time, objects to the original

claim language in claim 21 reciting “degrees of reflection of a laser light.” Applicants therefore respectfully traverse this rejection first, because the Examiner has provided no explanation for why he did not consider this language from the claim in the previous seven Office Actions, and second, because it is improper for the Examiner to reject the claims under Section 112 for what appears to be nothing more than an antecedent basis objection.

Applicants have therefore amended claim 21 herein to correct a lack of antecedent basis for the phrase “the laser light.” Applicants have otherwise further amended the claim to only improve the grammar of the claim. The Examiner should see though, that there have been no substantive amendments to this claim. The claim phrase the Examiner finds confusing, namely, “degrees of reflection of a laser light,” has been deleted, and therefore all of Applicants’ previous remarks regarding the Examiner’s interpretation of these claims are therefore still relevant, and incorporated by reference herein.

Specifically, Applicants again remind the Examiner that the laser light recited in the claim is not a structural limitation of the recited thin film transistor device. The structural features recited in the claim pertain to the thickness of the insulation film, and the reflectivity of the other recited regions based on this film thickness. All of these limitations are structural characteristics of the device, and the Examiner’s repeated attempts to read additional limitations into these claims relating to the laser light are improper. The Examiner is responsible for considering the recited features of the claimed

device, and may not assign additional limitations according to what potential uses the Examiner envisions for the device. Accordingly, reconsideration and withdrawal of the outstanding Section 112 rejection is respectfully requested.

With respect to the Examiner’s remarks regarding what “other layers” may be “between the laser and the recited low impurity and source/drain regions,” Applicants traverse what appears to be a further attempt to add limitations to the recited claims. Applicants are not required to define every possible order to the various recited layers, or what additional layers may or may not be excluded from such a structure. Once again, Applicants remind the Examiner that he may not require additional limitations when the prior art does not meet the limitations that are actually claimed. The Examiner has in no way established how the specific structure recited in the claims is indefinite to the extent where one skilled in the art would not be able to understand the claim structure when read in light of the present Specification. The Examiner does not even appear to have applied this required standard in asserting the outstanding Section 112 rejection. Accordingly, the rejection is further deficient on its face, and must be withdrawn for these additional reasons.

Claims 16-17 and 25-26, “as being best understood in view of the claim objections,” again stand rejected under 35 U.S.C. 102(b) as being anticipated by Takemura (U.S. 5,719,065). Applicants first respectfully traverse this rejection because no claim objections have been asserted in the outstanding Office Action. Applicants further traverse the rejection for at least the reasons of record (all of the previous

arguments against Takemura being incorporated by reference herein), and as follows. Takemura simply does not read upon the present invention.

The Examiner's remarks on page 7 of the outstanding Office Action demonstrate an unreasonable and incorrect reading of the Takemura reference. The Examiner erroneously asserts that TFT1 in Fig. 5A of Takemura reads upon claim 16 of the present invention. The assertion appears to be based on the statement (page 7, lines 5-7) that Takemura's gate insulating film 104 is shown to be "covering all the surfaces of the channel region and the low density impurity regions of the 'identified portions' of the regions y or y' in this semiconductor layer." This statement is erroneous because the film 104 in TFT1 is unambiguously shown to cover less than half of the low density y-region in Fig. 5A. Claim 16 of the present invention, on the other hand, expressly recites that the first insulation film covers all of the area above the low density impurity regions. This point was clearly argued in Applicants' previous remarks, and there was nothing "implicit" about them, as the Examiner alleges. Accordingly, the rejection based on Takemura must be withdrawn for at least these reasons.

With respect to the Examiner's assertions relating to "a plurality of low impurity regions," these remarks are irrelevant to the rejection of claim 16 based on Fig. 5A of Takemura. The Examiner has not cited to any teaching or suggestion that indicates the low density regions (identified in the area y under the TFT1 in Fig. 5A) comprise a plurality of low density regions of different impurities. And even if this theory could be supported, it still fails to establish a case of anticipation against the present invention.

The Examiner alleges no more than what may be possible within the art. The Examiner has not identified, however, that Takemura actually teaches or suggests such a particular structural configuration according to this theory. This deficiency in the rejection is particularly significant because the rejection is based on anticipation. The Examiner has not met his burden though to establish that the reference itself affirmatively teaches the exact structure alleged. Takemura simply does not affirmatively teach that the y-region under the TFT1 in Fig. 5A is actually a “plurality” of different concentrations of low density impurities. In the event the Examiner chooses to simply change the grounds of rejection of anticipation to obviousness, Applicants point out that Takemura does not suggest either that Fig. 5A meets the Examiner’s theory. Accordingly, for at least these additional reasons, the rejection is deficient, and should be withdrawn.

Because the prosecution of this case has been subject to significant delays by the Patent Office, in the interests of expediting prosecution only, Applicants have further amended independent claim 16 herein for the purposes of expediting prosecution only. The Examiner should see that all of the asserted theories regarding the unsupported “pluralities of low impurity regions” cannot be relevant.

Claim 16 now clearly defines the first insulation film to cover all of the surface of the channel and low density impurity regions up to a nearest edge of each of the respective source and drain regions. The Examiner should see that none of the asserted theories regarding potential “pluralities of different low density regions” can

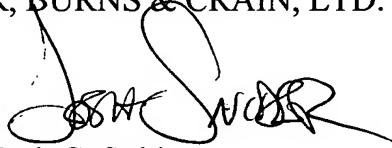
read upon this language. Just as previously argued, this language is fully supported by the same drawings of the present Specification, and their accompanying text. Accordingly, for these still further reasons, Applicants submit that the outstanding rejection based on Takemura must be withdrawn.

For all of the foregoing reasons, Applicants submit that this Application, including claims 16-17, 21, and 24-26, is in condition for allowance, which is respectfully requested. The Examiner is invited to contact the undersigned attorney if an interview would help expedite prosecution.

Respectfully submitted,

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